

Search Notes**Application/Control No.**

10/521,594

Examiner

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**Applicant(s)/Patent under
Reexamination**

IWASAKI ET AL.

Art Unit

1791

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
425	388	6/22/2009	EHL
264/549,550,572,554		6/22/2009	EHL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
264/549,550,572,553	6/22/2009	EHL
425/388	6/22/2009	EHL
UPDATED	6/22/2009	EHL